

<b>Notice of References Cited</b>	Application/Control No. 10/535,426	Applicant(s)/Patent Under Reexamination YOSHIDA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0242481	10-2006	Hwang et al.	714/710
*	B	US-2004/0165495	08-2004	Park et al.	369/047.14
*	C	US-2004/0105363	06-2004	Ko et al.	369/047.14
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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